

<b>Notice of References Cited</b>	Application/Control No. 10/806,267		Applicant(s)/Patent Under Reexamination OHNO, TAKASHI	
	Examiner Tae H. Yoon		Art Unit 1714	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0239919 A1	10-2005	Ono, Takashi	523/160
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